

Search Notes

Application/Control No.

10/802,253

Examiner

Hien N. Nguyen

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.33	7/20/2005	HN
365	185.29		
365	185.17		
257	314		HN
257	315		HN
257	316		HN
257	317		HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/20/2005	HN